

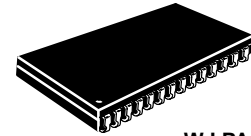
# 256K x 4 Bit Fast Static Random Access Memory

The MCM6728B is a 1,048,576 bit static random access memory organized as 262,144 words of 4 bits. This device is fabricated using high performance silicon-gate BiCMOS technology. Static design eliminates the need for external clocks or timing strobes.

This device meets JEDEC standards for functionality and revolutionary pinout, and is available in a 400 mil plastic small-outline J-leaded package.

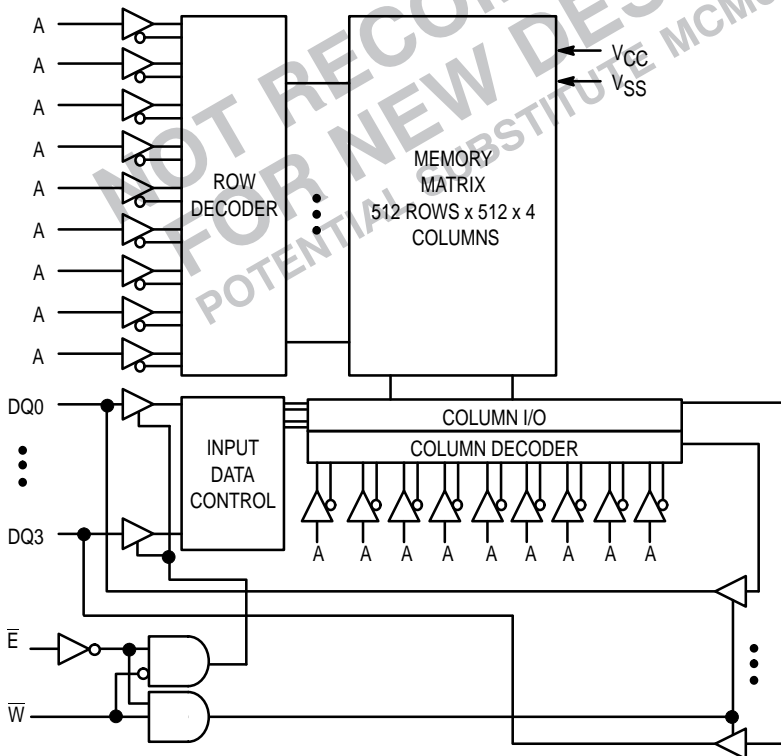
- Single 5 V ± 10% Power Supply
- Fully Static — No Clock or Timing Strokes Necessary
- All Inputs and Outputs Are TTL Compatible
- Three State Outputs
- Fast Access Times: 8, 10, 12 ns
- Center Power and I/O Pins for Reduced Noise

## MCM6728B



**WJ PACKAGE**  
**400 MIL SOJ**  
**CASE 810-03**

### BLOCK DIAGRAM



### PIN ASSIGNMENT

A	1	28	A
A	2	27	A
A	3	26	A
A	4	25	A
E	5	24	A
DQ0	6	23	DQ3
VCC	7	22	VSS
VSS	8	21	VCC
DQ1	9	20	DQ2
W	10	19	A
A	11	18	A
A	12	17	A
A	13	16	A
A	14	15	A

### PIN NAMES

A0 – A17	Address Input
E	Chip Enable
W	Write Enable
DQ0 – DQ3	Data Input/Output
VCC	+ 5 V Power Supply
VSS	Ground
NC	No Connection

**TRUTH TABLE** (X = Don't Care)

$\bar{E}$	$\bar{W}$	Mode	V <sub>CC</sub> Current	Output	Cycle
H	X	Not Selected	I <sub>SB1</sub> , I <sub>SB2</sub>	High-Z	—
L	H	Read	I <sub>CCA</sub>	D <sub>out</sub>	Read Cycle
L	L	Write	I <sub>CCA</sub>	High-Z	Write Cycle

**ABSOLUTE MAXIMUM RATINGS** (See Note)

Rating	Symbol	Value	Unit
Power Supply Voltage	V <sub>CC</sub>	- 0.5 to + 7.0	V
Voltage Relative to V <sub>SS</sub> for Any Pin Except V <sub>CC</sub>	V <sub>in</sub> , V <sub>out</sub>	- 0.5 to V <sub>CC</sub> + 0.5	V
Output Current	I <sub>out</sub>	± 30	mA
Power Dissipation	P <sub>D</sub>	1.0	W
Temperature Under Bias	T <sub>bias</sub>	- 10 to + 85	°C
Operating Temperature	T <sub>A</sub>	0 to + 70	°C
Storage Temperature—Plastic	T <sub>stg</sub>	- 55 to + 125	°C

NOTE: Permanent device damage may occur if ABSOLUTE MAXIMUM RATINGS are exceeded. Functional operation should be restricted to RECOMMENDED OPERATING CONDITIONS. Exposure to higher than recommended voltages for extended periods of time could affect device reliability.

This device contains circuitry to protect the inputs against damage due to high static voltages or electric fields; however, it is advised that normal precautions be taken to avoid application of any voltage higher than maximum rated voltages to these high-impedance circuits.

This BiCMOS memory circuit has been designed to meet the dc and ac specifications shown in the tables, after thermal equilibrium has been established. The circuit is in a test socket or mounted on a printed circuit board and transverse air flow of at least 500 linear feet per minute is maintained.

**DC OPERATING CONDITIONS AND CHARACTERISTICS**

(V<sub>CC</sub> = 5.0 V ± 10%, T<sub>A</sub> = 0 to 70°C, Unless Otherwise Noted)

**RECOMMENDED OPERATING CONDITIONS**

Parameter	Symbol	Min	Typ	Max	Unit
Supply Voltage (Operating Voltage Range)	V <sub>CC</sub>	4.5	5.0	5.5	V
Input High Voltage	V <sub>IH</sub>	2.2	—	V <sub>CC</sub> + 0.3**	V
Input Low Voltage	V <sub>IL</sub>	- 0.5*	—	0.8	V

\* V<sub>IL</sub> (min) = - 0.5 V dc; V<sub>IL</sub> (min) = - 2.0 V ac (pulse width ≤ 2.0 ns) for I ≤ 20.0 mA.

\*\* V<sub>IH</sub> (max) = V<sub>CC</sub> + 0.3 V dc; V<sub>IH</sub> (max) = V<sub>CC</sub> + 2 V ac (pulse width ≤ 2.0 ns) for I ≤ 20.0 mA.

**DC CHARACTERISTICS**

Parameter	Symbol	Min	Max	Unit
Input Leakage Current (All Inputs, V <sub>in</sub> = 0 to V <sub>CC</sub> )	I <sub>kg(I)</sub>	—	± 1.0	μA
Output Leakage Current ( $\bar{E}$ = V <sub>IH</sub> , V <sub>out</sub> = 0 to V <sub>CC</sub> )	I <sub>kg(O)</sub>	—	± 1.0	μA
Output Low Voltage (I <sub>OL</sub> = + 8.0 mA)	V <sub>OL</sub>	—	0.4	V
Output High Voltage (I <sub>OH</sub> = - 4.0 mA)	V <sub>OH</sub>	2.4	—	V

**POWER SUPPLY CURRENTS**

Parameter	Symbol	6728B-8	6728B-10	6728B-12	Unit	Notes
AC Active Supply Current (I <sub>out</sub> = 0 mA) (V <sub>CC</sub> = max, f = f <sub>max</sub> )	I <sub>CCA</sub>	195	165	155	mA	1, 2, 3
Active Quiescent Current ( $\bar{E}$ = V <sub>IL</sub> , V <sub>CC</sub> = max, f = 0 MHz)	I <sub>CC2</sub>	90	90	90	mA	
AC Standby Current ( $\bar{E}$ = V <sub>IH</sub> , V <sub>CC</sub> = max, f = f <sub>max</sub> )	I <sub>SB1</sub>	60	60	60	mA	1, 2, 3
CMOS Standby Current (V <sub>CC</sub> = max, f = 0 MHz, $\bar{E}$ ≥ V <sub>CC</sub> - 0.2 V, V <sub>in</sub> ≤ V <sub>SS</sub> + 0.2 V, or ≥ V <sub>CC</sub> - 0.2 V)	I <sub>SB2</sub>	20	20	20	mA	

NOTES:

- Reference AC Operating Conditions and Characteristics for input and timing (V<sub>IH</sub>/V<sub>IL</sub>, t<sub>r</sub>/t<sub>f</sub>, pulse level 0 to 3.0 V, V<sub>IH</sub> = 3.0 V).
- All addresses transition simultaneously low (LSB) and then high (MSB).
- Data states are all zero.

**CAPACITANCE** (f = 1.0 MHz, dV = 3.0 V, T<sub>A</sub> = 25°C, Periodically Sampled Rather Than 100% Tested)

Parameter	Symbol	Typ	Max	Unit
Address Input Capacitance	C <sub>in</sub>	—	6	pF
Control Pin Input Capacitance	C <sub>in</sub>	—	6	pF
Input/Output Capacitance	C <sub>I/O</sub>	—	8	pF

**AC OPERATING CONDITIONS AND CHARACTERISTICS**

(V<sub>CC</sub> = 5.0 V ± 10%, T<sub>A</sub> = 0 to + 70°C, Unless Otherwise Noted)

Input Timing Measurement Reference Level ..... 1.5 V      Output Timing Measurement Reference Level ..... 1.5 V  
 Input Pulse Levels ..... 0 to 3.0 V      Output Load ..... See Figure 1A  
 Input Rise/Fall Time ..... 2 ns

**READ CYCLE TIMING** (See Notes 1 and 2)

Parameter	Symbol	6728B-8		6728B-10		6728B-12		Unit	Notes
		Min	Max	Min	Max	Min	Max		
Read Cycle Time	t <sub>AVAV</sub>	8	—	10	—	12	—	ns	3
Address Access Time	t <sub>AVQV</sub>	—	8	—	10	—	12	ns	
Enable Access Time	t <sub>ELQV</sub>	—	8	—	10	—	12	ns	
Output Hold from Address Change	t <sub>AXQX</sub>	3	—	3	—	3	—	ns	
Enable Low to Output Active	t <sub>ELQX</sub>	3	—	3	—	3	—	ns	4,5,6
Enable High to Output High-Z	t <sub>EHQZ</sub>	0	4	0	5	0	6	ns	4,5,6

NOTES:

1.  $\bar{W}$  is high for read cycle.
2. For common I/O applications, minimization or elimination of bus contention conditions is necessary during read and write cycles.
3. All read cycle timings are referenced from the last valid address to the first transitioning address.
4. At any given voltage and temperature, t<sub>EHQZ</sub> max < t<sub>ELQX</sub> min, for a given device.
5. Transition is measured 200 mV from steady-state voltage with load of Figure 1B.
6. This parameter is sampled and not 100% tested.
7. Device is continuously selected ( $\bar{E} = V_{IL}$ ).
8. Addresses valid prior to or coincident with  $\bar{E}$  going low.

**AC TEST LOADS**

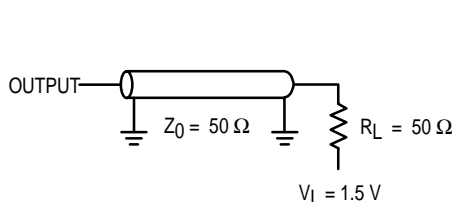


Figure 1A

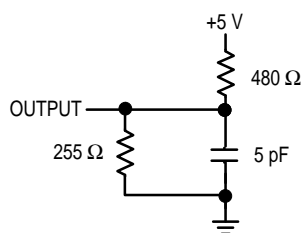
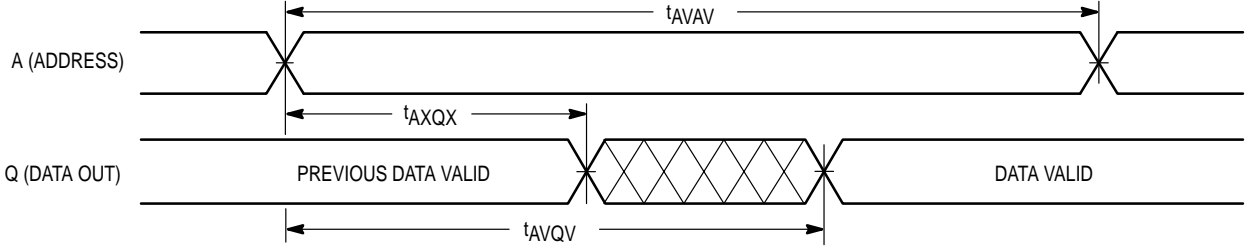


Figure 1B

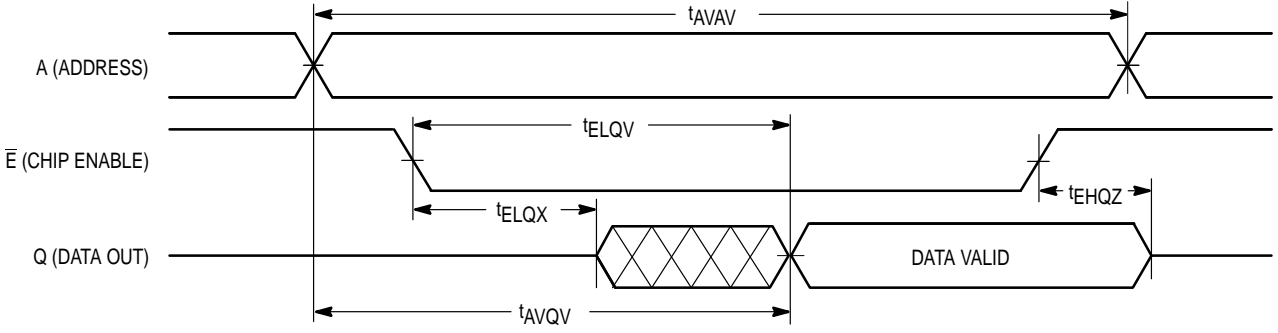
**TIMING LIMITS**

The table of timing values shows either a minimum or a maximum limit for each parameter. Input requirements are specified from the external system point of view. Thus, address setup time is shown as a minimum since the system must supply at least that much time (even though most devices do not require it). On the other hand, responses from the memory are specified from the device point of view. Thus, the access time is shown as a maximum since the device never provides data later than that time.

**READ CYCLE 1 (See Note 7)**



**READ CYCLE 2 (See Note 8)**



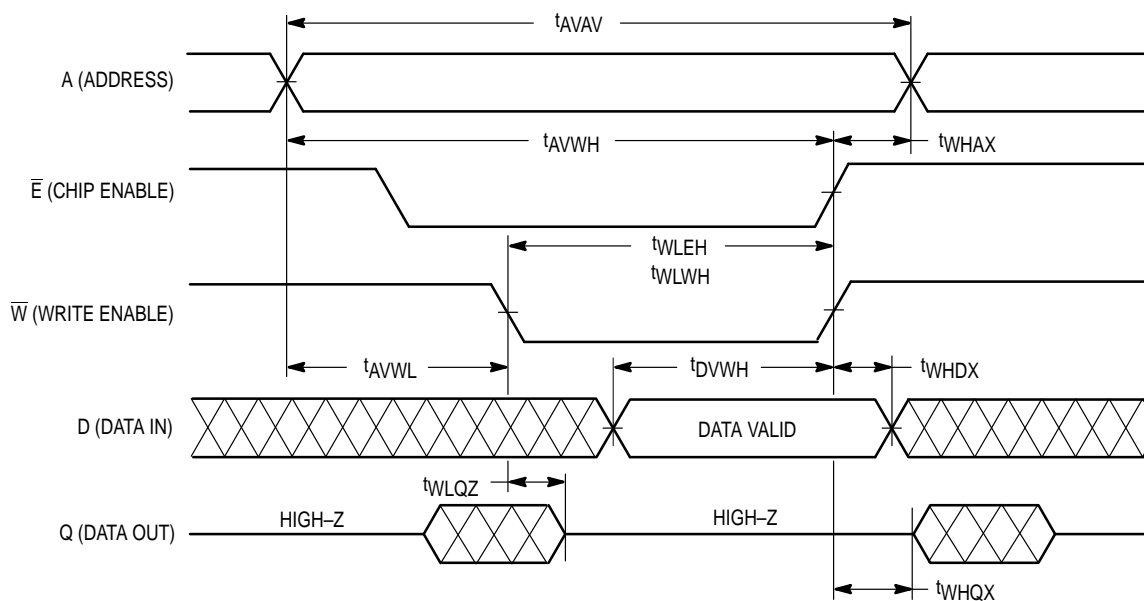
**WRITE CYCLE 1** ( $\overline{W}$  Controlled, See Notes 1 and 2)

Parameter	Symbol	6728B-8		6728B-10		6728B-12		Unit	Notes
		Min	Max	Min	Max	Min	Max		
Write Cycle Time	$t_{AVAV}$	8	—	10	—	12	—	ns	3
Address Setup Time	$t_{AVWL}$	0	—	0	—	0	—	ns	
Address Valid to End of Write	$t_{AVWH}$	8	—	9	—	10	—	ns	
Write Pulse Width	$t_{WLWH}$ , $t_{WLEH}$	8	—	9	—	10	—	ns	
Data Valid to End of Write	$t_{DVWH}$	4	—	5	—	6	—	ns	
Data Hold Time	$t_{WHDX}$	0	—	0	—	0	—	ns	
Write Low to Data High-Z	$t_{WLQZ}$	0	4	0	5	0	6	ns	4,5,6
Write High to Output Active	$t_{WHQX}$	3	—	3	—	3	—	ns	4,5,6
Write Recovery Time	$t_{WHAX}$	0	—	0	—	0	—	ns	

NOTES:

1. A write occurs during the overlap of  $\overline{E}$  low and  $\overline{W}$  low.
2. For common I/O applications, minimization or elimination of bus contention conditions is necessary during read and write cycles.
3. All write cycle timings are referenced from the last valid address to the first transitioning address.
4. Transition is measured 200 mV from steady-state voltage with load of Figure 1B.
5. This parameter is sampled and not 100% tested.
6. At any given voltage and temperature,  $t_{WLQZ} \text{ max} < t_{WHQX} \text{ min}$  both for a given device and from device to device.

**WRITE CYCLE 1**



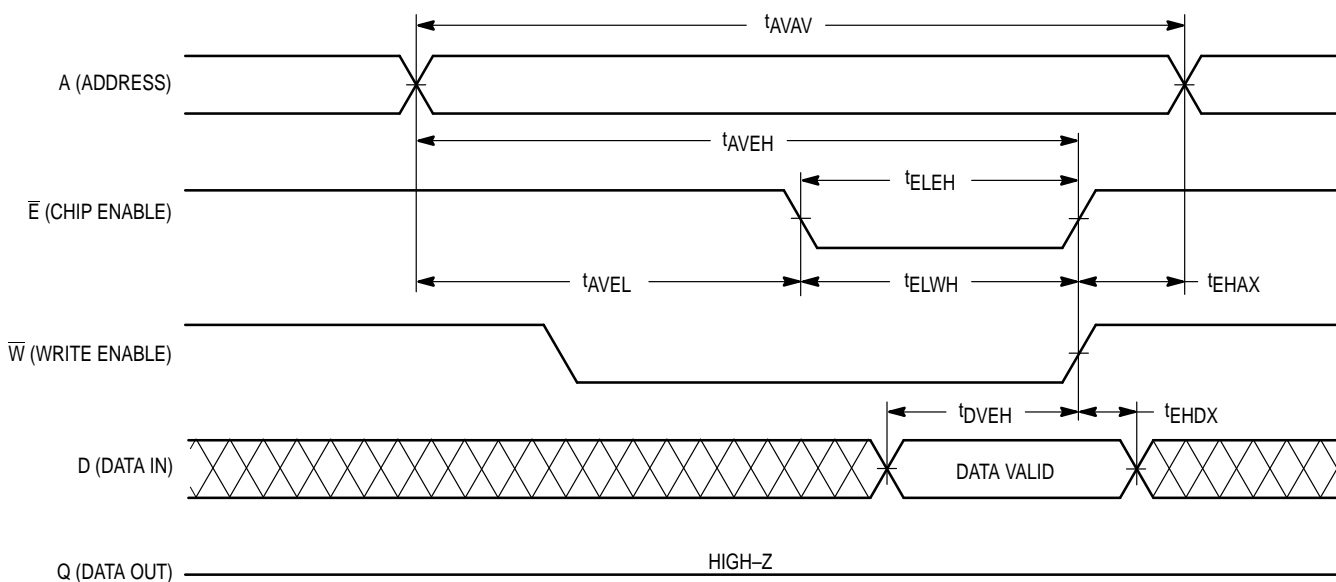
**WRITE CYCLE 2** ( $\bar{E}$  Controlled, See Notes 1 and 2)

Parameter	Symbol	6728B-8		6728B-10		6728B-12		Unit	Notes
		Min	Max	Min	Max	Min	Max		
Write Cycle Time	$t_{AVAV}$	8	—	10	—	12	—	ns	3
Address Setup Time	$t_{AVEL}$	0	—	0	—	0	—	ns	
Address Valid to End of Write	$t_{AVEH}$	7	—	8	—	9	—	ns	
Enable to End of Write	$t_{ELEH}$ , $t_{ELWH}$	7	—	8	—	9	—	ns	4,5
Data Valid to End of Write	$t_{DVEH}$	4	—	5	—	6	—	ns	
Data Hold Time	$t_{EHDX}$	0	—	0	—	0	—	ns	
Write Recovery Time	$t_{EHAX}$	0	—	0	—	0	—	ns	

**NOTES:**

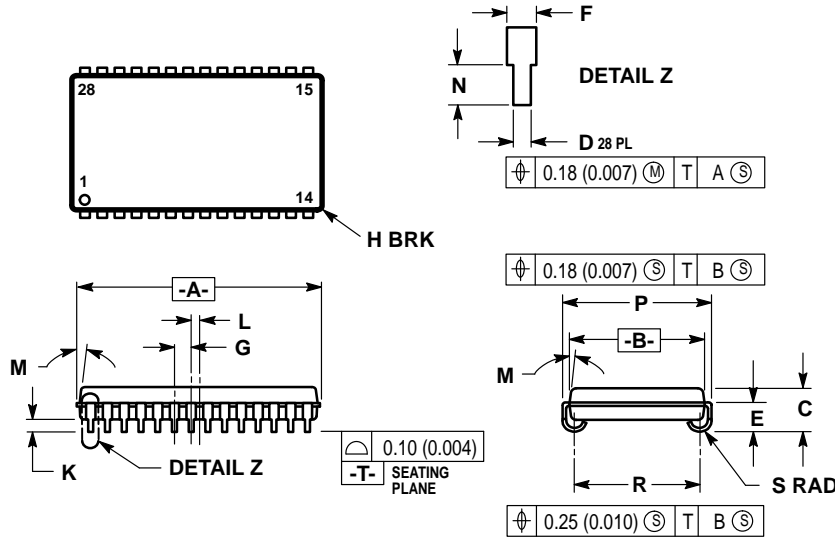
1. A write occurs during the overlap of  $\bar{E}$  low and  $\bar{W}$  low.
2. For common I/O applications, minimization or elimination of bus contention conditions is necessary during read and write cycles.
3. All write cycle timings are referenced from the last valid address to the first transitioning address.
4. If  $\bar{E}$  goes low coincident with or after  $\bar{W}$  goes low, the output will remain in a high impedance condition.
5. If  $\bar{E}$  goes high coincident with or before  $\bar{W}$  goes high, the output will remain in a high impedance condition.

**WRITE CYCLE 2**



## PACKAGE DIMENSIONS

**28-LEAD  
400 MIL SOJ  
CASE 810-03**

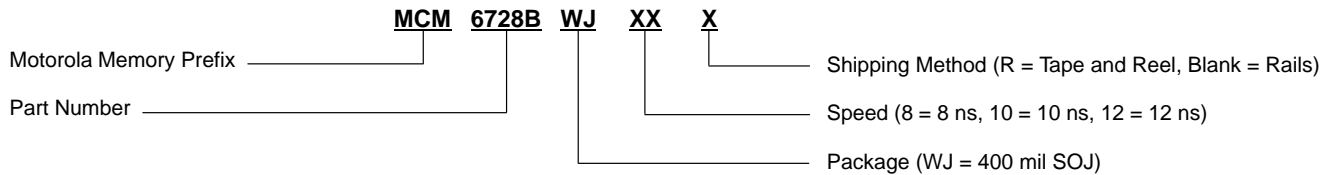


**NOTES:**

1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
2. DIMENSION A & B DO NOT INCLUDE MOLD PROTRUSION. MOLD PROTRUSION SHALL NOT EXCEED 0.15 (0.006) PER SIDE.
3. CONTROLLING DIMENSION: INCH.
4. DIM R TO BE DETERMINED AT DATUM -T-.
5. 810-01 AND -02 OBSOLETE, NEW STANDARD 810-03.

DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	18.29	18.54	0.720	0.730
B	10.04	10.28	0.395	0.405
C	3.26	3.75	0.128	0.148
D	0.39	0.50	0.015	0.020
E	2.24	2.48	0.088	0.098
F	0.67	0.81	0.026	0.032
G	1.27 BSC		0.050 BSC	
H	—	0.50	—	0.020
K	0.89	1.14	0.035	0.045
L	0.64 BSC		0.025 BSC	
M	0°	5°	0°	5°
N	0.76	1.14	0.030	0.045
P	11.05	11.30	0.435	0.445
R	9.15	9.65	0.360	0.380
S	0.77	1.01	0.030	0.040

## ORDERING INFORMATION (Order by Full Part Number)



Full Part Numbers — MCM6728BWJ8    MCM6728BWJ10    MCM6728BWJ12  
    MCM6728BWJ8R    MCM6728BWJ10R    MCM6728BWJ12R

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MCM6728B/D

